

Application/Control No.	Applicant(s)/Patent (ınder
09/982,926	NI, SHIH-HSIUNG	
Examiner	Art Unit	
Lina Yano	2665	

SEARCHED				
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Consulted Alpus Hsu	12/13/2005	LY	
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